

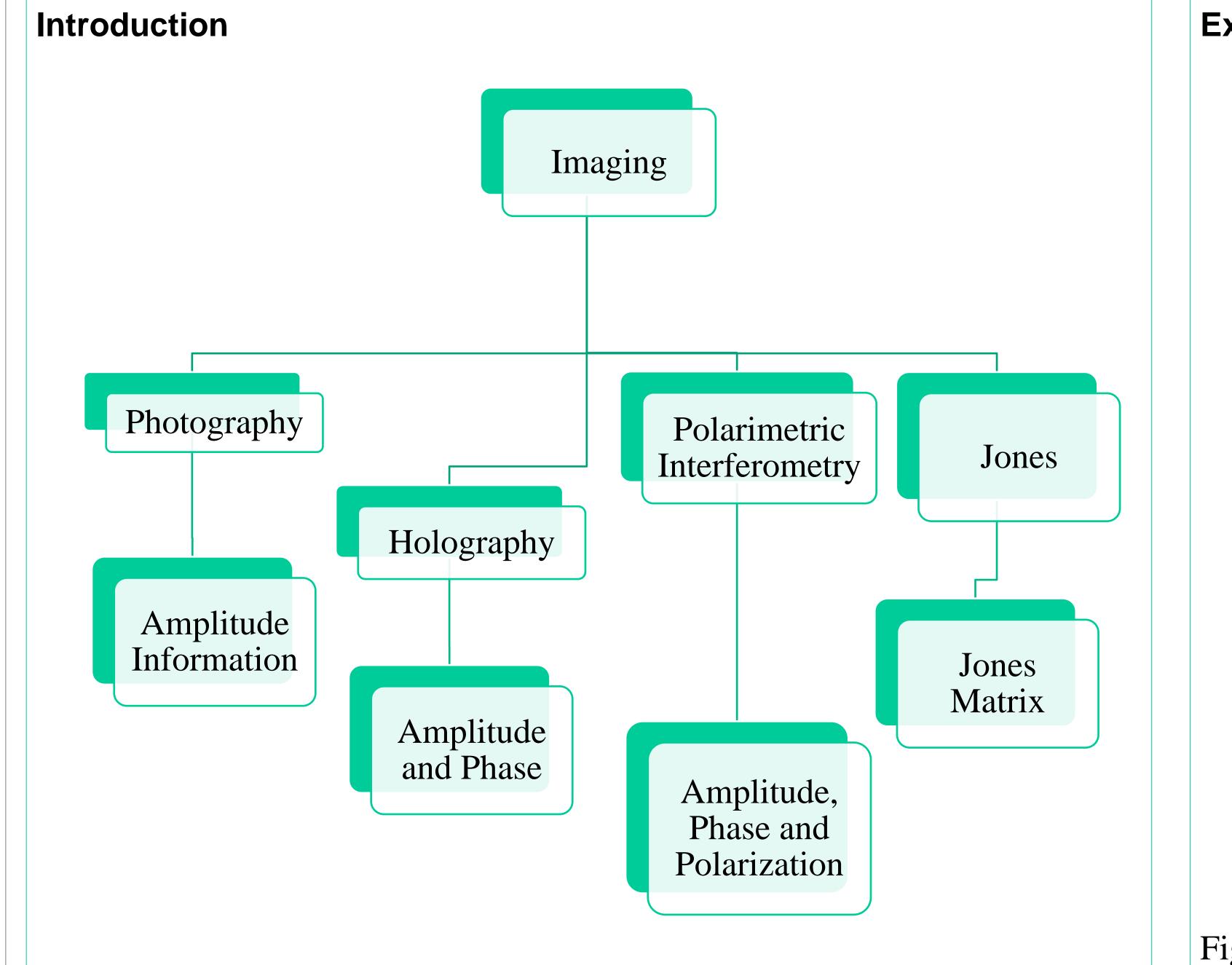
# **Single-Shot Jones Matrix Microscopy**

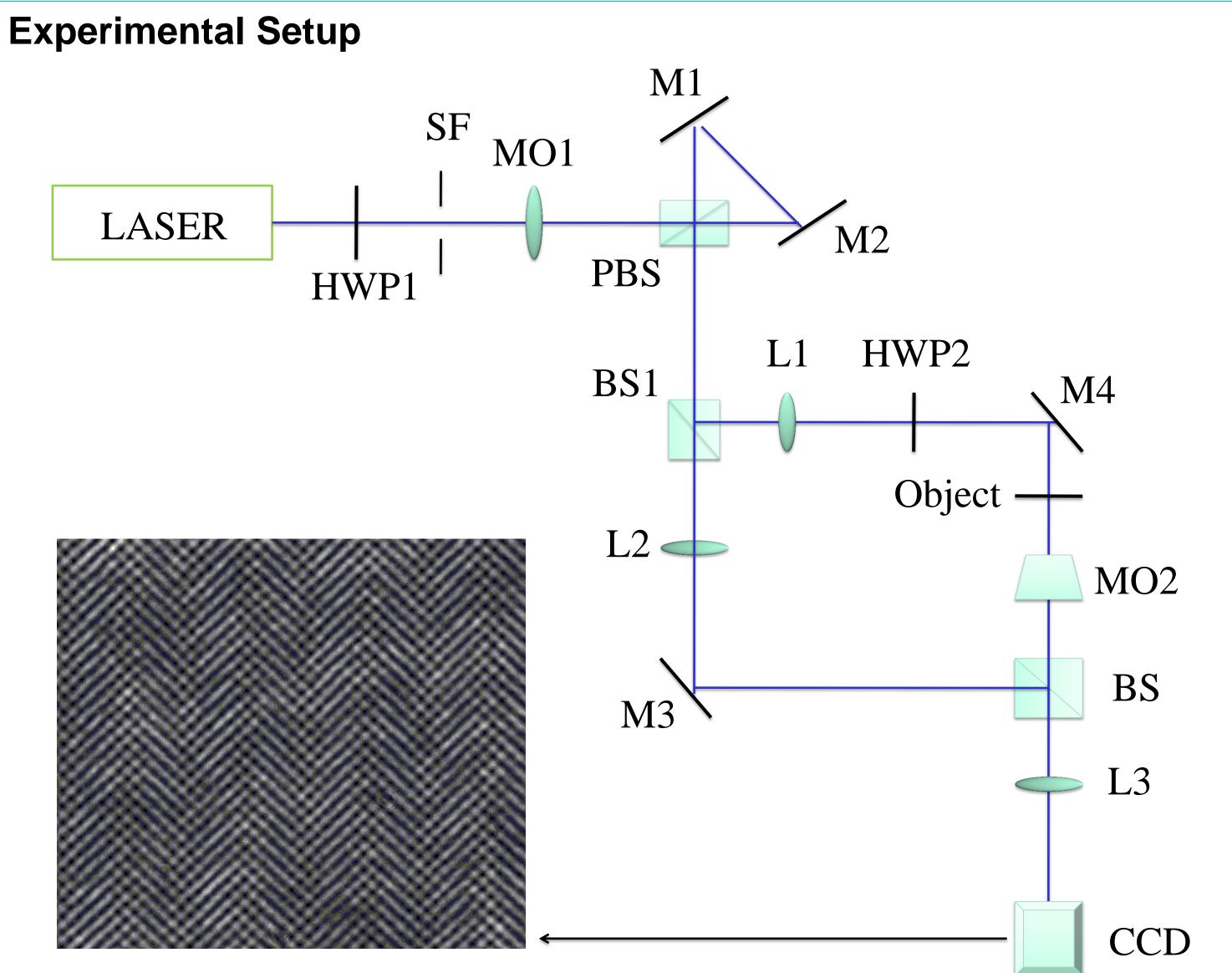
S.K.Gautam<sup>1\*</sup>, P. Panchal<sup>1</sup>, P. Mishra<sup>1</sup>, D.N. Naik<sup>1</sup>, C.S. Narayanamurthy<sup>1</sup>, R.K. Singh<sup>2</sup>

<sup>1</sup> Applied and Adaptive Optics lab, Department of Physics, Indian Institute of Space Science and Technology, India <sup>2</sup> Department of Physics, Indian Institute of Technology (BHU), Varanasi, Uttar Pradesh, India \*Corresponding author: suryagautam89@gmail.com



**Abstract** Field based polarization measurement is essential to understand and quantify the optical response of any target sample. The method discussed here is digital holography microscopy that enables us to quantify spatially the Jones Matrix of a transparent anisotropic sample. Our method provides precise information about the polarization properties in a single shot, therefore, well suited for a dynamic biological specimen.





### Principle

The Jones Matrix formalism says that an input light field with  $E_{ix}$  and  $E_{iy}$  and the output field upon emerging from an object are related as

$$\begin{bmatrix} E_{ox} \\ E_{oy} \end{bmatrix} = \begin{bmatrix} J_{xx} & J_{xy} \\ J_{yx} & J_{yy} \end{bmatrix} \begin{bmatrix} E_{ix} \\ E_{iy} \end{bmatrix}$$

Fig.2. Experimental Setup : Single Shot Jones Matrix MicroscopyMicroscope Objective MO1 and MO2, Mirror M1, M2, M3 and M4, Lens L,L1, L2 and L3, Beam Splitter BS1 and BS, Spatial Filter SF, Polarizing BeamSplitter PBS, Half Wave Plate HWP1 and HWP2.

A polarizer oriented at  $0^0$  and  $45^0$  degree is used as a sample .

### **Experimental Results**



Where  $J_{ij} = |J_{ij}|e^{\phi_{ij}}$  is the Jones matrix element and  $\Phi$  is a phase with i, j = x, y.

For +45<sup>0</sup> degree polarized input light output field can be written as

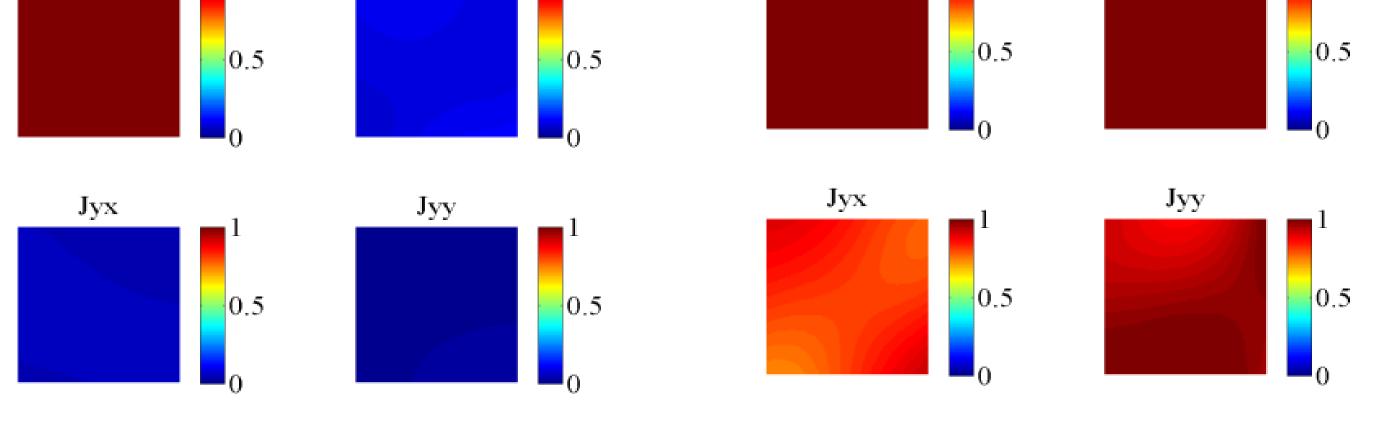
$$\begin{bmatrix} E_{+45x} \\ E_{+45y} \end{bmatrix} = \begin{bmatrix} J_{xx} & J_{xy} \\ J_{yx} & J_{yy} \end{bmatrix} \begin{bmatrix} 1 \\ 1 \end{bmatrix} = JE_{+45}$$
(1)

Similarly for -45<sup>0</sup> degree polarized input light output field can be written as

$$\begin{bmatrix} E_{-45x} \\ E_{-45y} \end{bmatrix} = \begin{bmatrix} J_{xx} & J_{xy} \\ J_{yx} & J_{yy} \end{bmatrix} \begin{bmatrix} 1 \\ -1 \end{bmatrix} = JE_{-45}$$
(2)

These two output fields are then interfered with the two reference beams having different carrier frequency Rx and Ry. Then the recorded multiplexed interference pattern can be written mathematically as

$$I = |IE_{45} + IE_{-45} + R_{\gamma} + R_{\gamma}|$$

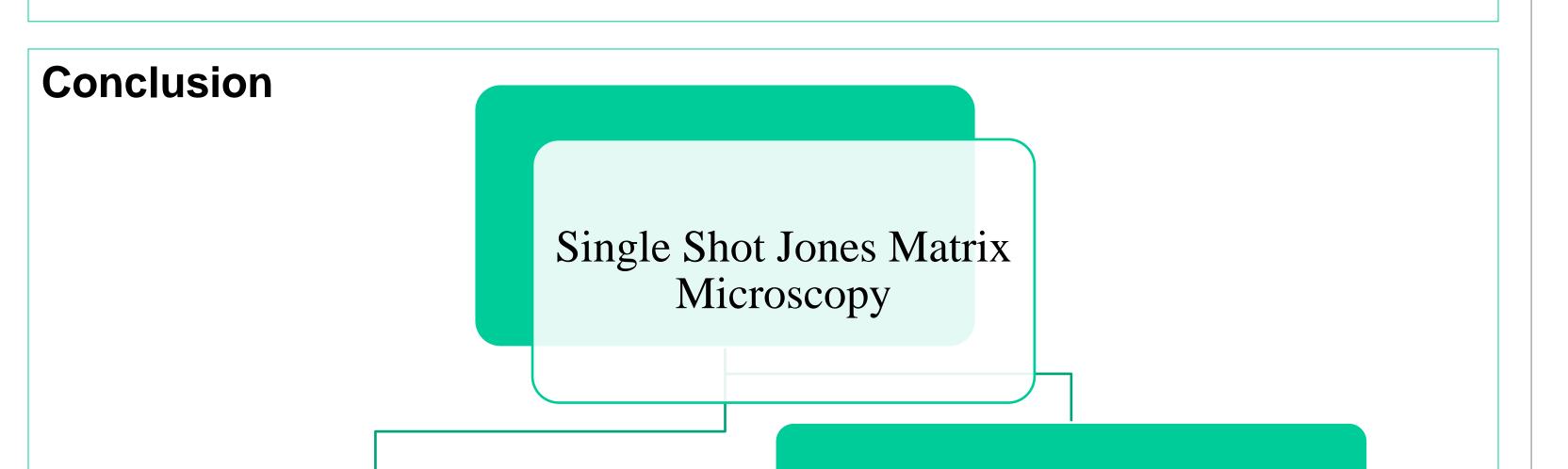


(a) Recovered Jones Matrix for  $0^0$ 

(b) Recovered Jones Matrix for 45<sup>0</sup>

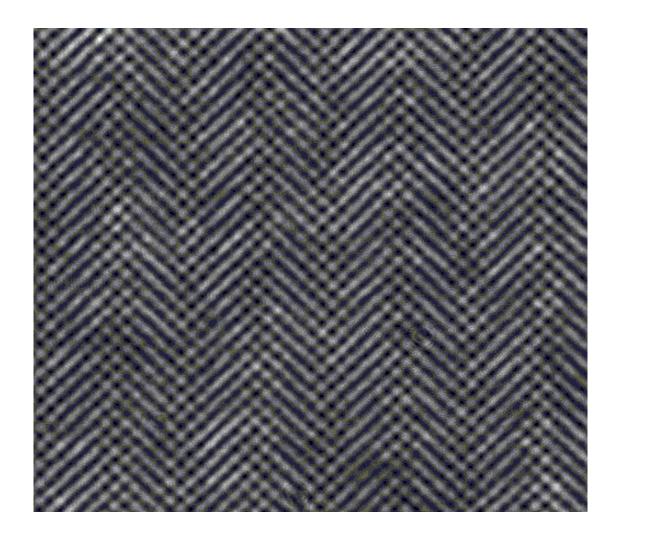
Single Shot

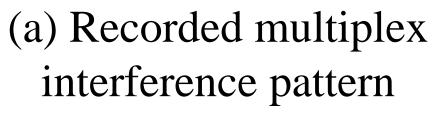
Fig.3 (a) and (b) show the Jones Matrix of a Polarizer oriented at 0<sup>0</sup> and 45<sup>0</sup> respectively

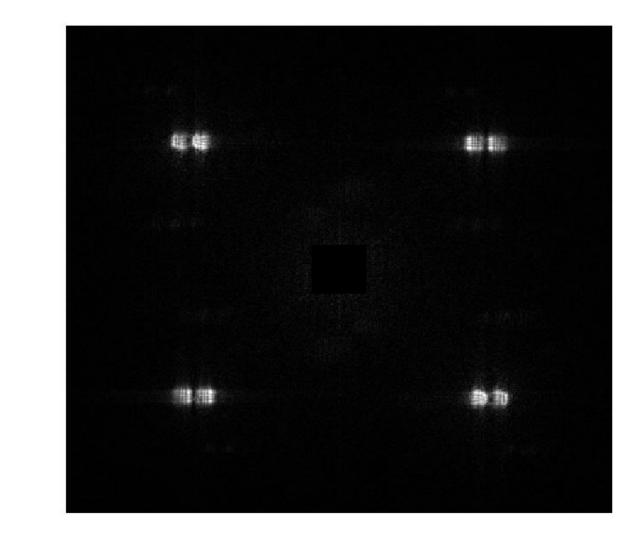


The recorded interferogram is then analyzed using Fourier fringe analysis to achieve the complete Jones matrix information. Multiplex interference pattern and its Fourier transform are shown in Fig.1 (a) and (b) respectively.

Fig.1







## (b) Fourier transform

Biological, anisotropic or birefringence sample

### References

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